



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 9
Test carried on 05.12.11 – 07.12.11

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{WFHM}$	Pos. [Ch.]	FWHM [keV]
A	13	4000	2.08	n.c.	2.05	n.c.	6019	
B	120	3500	2.11	n.c.	2.07	n.c.	6439	
C	94	4500*	2.04	n.c.	1.98	n.c.	6150	
D	102	3500	2.43	n.c.	2.18	n.c.	6527	
E	129	4000	2.07	n.c.	1.86	n.c.	6448	
F	112	4500*	2.19	n.c.	1.98	n.c.	7175	
G	135	3500	2.03	n.c.	2.00	n.c.	6735	

Operational Temperature: -169.8 °C

Date: 07.12.2011

Tested by:
/I.Kojouharov/

Assembly and test remarks:

Regular tests after assembly at RIKEN.

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau=6 \mu\text{s}$

ADC – 4801A(RIKEN),

MCA – PC98B

Source - ^{60}Co